



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of
Bernard Fay et al.

Serial No.: 09/881,026

Group Art Unit: Not Known

Filed: June 15, 2001

Examiner: Not Known

For: AUTOMATED OVERLAY METROLOGY SYSTEM

Commissioner of Patents and Trademarks
Washington, D.C. 20231

PRELIMINARY AMENDMENT

Sir:

Prior to an official action on the merits of the
above-identified application, please amend the
application as follows:

In the specification:

Please substitute the following paragraphs for the
paragraphs of the application as originally filed at
the locations respectively indicated. A marked-up copy
of these requested changes is provided as an appendix
to this preliminary amendment.

Page 14, line 15+:

61
A simulation of the FFT amplitude variation of
spectral reflectance data from the pattern of Figure 2A
is shown in Figure 3 and a simulation of FFT amplitude
variation of spectral reflectance data from the pattern
of Figure 2B is shown in Figure 4. It is assumed for
purposes of this discussion that the differently shaded
portions 22, 24 of Figure 2A (and 2B) have different
reflectivity and that the marks include at least one

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